

**Notice of References Cited**

Application/Control No.

09/988,107

Applicant(s)/Patent Under  
Reexamination  
HACHISU ET AL.

Examiner

A. Sefer

Art Unit

2826

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A		US-6,337,730	01-2002	Ozaki et al	349/156
B		US-6,184,967	02-2001	Lagerwall et al	349/155
C		US-6,603,528	08-2003	Tanaka et al	349/155
D		US-4,682,858	07-1987	Kanbe et al	350/334
E		US-5,699,139	12-1997	Aastuen et al	349/156
F		US-			
G		US-			
H		US-			
I		US-			
J		US-			
K		US-			
L		US-			
M		US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-122100	04-2000	Japan	Suzuki et al	
	O	JP 2000-235187	08-2000	Japan	Hachisu et al	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a) )  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.